

e filing Date : 8/27/2004

## ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

### Title of Invention

METHODOLOGY OF QUANTIFICATION OF TRANSMISSION  
PROBABILITY FOR MINORITY CARRIER COLLECTION IN A  
SEMICONDUCTOR CHIP

Application Number :

Confirmation Number:

First Named Applicant: Anne Watson

Attorney Docket Number: BUR920040120US1






Art Unit: 2825

Examiner: P. KIK

Search string: ( 6493850 or 6553542 or 6490709 or 5559060 or 5638286 or 20030074641 ).pn


### US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	1	6493850	2002-12-10	Venugopal et al.			
	2	6553542	2003-04-22	Ramaswamy et al.			
	3	6490709	2002-12-03	Kimura et al.			
	4	5559060	1996-09-24	Alsmeier et al.			
	5	5638286	1997-06-10	Fujimoto			

### US Published Applications

Note: Applicant is not required to submit a paper copy of cited US Published Applications

init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
	1	20030074641	2003-04-17	Kimura et al.			

Signature



Examiner Name

Date



6/23/06

**INFORMATION DISCLOSURE CITATION**  
(Use several sheets if necessary)

Docket Number (Optional) <b>BUR920040120US1</b>	Application Number <b>10/711,143</b>
Applicant(s) <b>A. Watson, et al.</b>	
Filing Date <b>August 27, 2004</b>	Group Art Unit <b>2825</b>

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE



**U.S. PATENT APPLICATION PUBLICATIONS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

**FOREIGN PATENT DOCUMENTS**

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
<i>PD</i>		JP2020039		Japan		<i>abstract</i>	<input checked="" type="checkbox"/>	

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>PD</i>		SUBSTRATE MODELING AND LUMPED SUBSTRATE RESISTANCE EXTRACTION FOR CMOS ESD/LATCHUP CIRCUIT SIMULATION, T. Li, et al., Coordinated Science Laboratory, Dept. of Electrical and Computer Engineering University of Illinois at Urbana-Champaign, Urbana, IL (1999), 6 pages; 1999 ACM.
<i>PD</i>		BIPOLAR TRANSISTOR ACTION AND TRANSPORT EFFECTS RELATING TO CMOS LATCHUP, G. Krieger, IEEE Transactions on Electron Devices, Vol. ED-34, No. 8, August 1987, pgs. 1719-1728

EXAMINER <i>Phellaker Mike</i>	DATE CONSIDERED <i>6/24/06</i>
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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							YES	NO

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

		PARASITIC LATERAL BIPOLAR TRANSISTORS IN CMOS, L. Deferm, et al., Solid-State Electronics, Vol. 32 No. 2, pgs 103-109, 1989.
		A NEW ANALYTICAL THREE-DIMENSIONAL MODEL FOR SUBSTRATE RESISTANCE IN CMOS LATCHUP STRUCTURES, M. Chen, et al., IEEE Transactions on Electron Devices, Vol. ED-33 No. 4 pgs. 489-493, April 1986.

EXAMINER

*Phallake Kulk*

DATE CONSIDERED

*6/24/2006*

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**U.S. PATENT APPLICATION PUBLICATIONS**



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	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

**OTHER DOCUMENTS**

(Including Author, Title, Date, Pertinent Pages, Etc.)

	STATIC AND TRANSIENT LATCHUP SIMULATION OF VLSI-CMOS WITH AN IMPROVED PHYSICAL DESIGN MODEL, M. Strzempa-Depre, et al., IEEE Transactions on Electron Devices, Vol. ED-34 No. 6, June 1987, pgs 1290-1296
	A CMOS MODEL FOR COMPUTER-AIDED CIRCUIT ANALYSIS AND DESIGN, J. W. Roberts, et al., IEEE Journal of Solid-State Circuits, Vol. 24, No. 1, February 1989, pgs 128-138

EXAMINER

*Phallaka Hike*

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*6/24/2006*

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							YES	NO

## OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

		CORRELATING THE CHANNEL, SUBSTRATE, GATE AND MINORITY-CARRIER CURRENTS IN MOSFETs, C. Hu et al., IEEE International, Solid-State Circuits Conference, Digest of Technical Papers February 1983, pgs. 88-90

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Phallaka Kik

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